

INFORMATION DISCLOSURE STATEMENT

Applicant	:	Smith, et al.
App. No.	:	Unknown
Filed	:	Herewith
For	:	STRUCTURE AND METHOD OF FABRICATING A TRANSISTOR HAVING A TRENCH GATE
Examiner	:	Unknown
Group Art Unit	:	Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing 4 references that are also enclosed. This Information Disclosure Statement is being filed within three months of the filing date of this application and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1), (b)(2), or (b)(4).

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 11/13/03

By: Karen J. Lenker

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.271A	APPLICATION NO. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Smith, et al.	
		FILING DATE Herewith	GROUP Unknown

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
		*					

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
		*						

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	Yanagisawa, et al.; TRENCH TRANSISTOR CELL WITH SELF-ALIGNED CONTACT (TSAC) FOR MEGABIT MOS DRAM; 1st LSI Division, NEC Corporation; 1120 Shimokuzawa, Sagamihara, Kanagawa 229, Japan; Pages 132-135.
	Landgraf, et al.; SCALABLE HIGH VOLTAGE TRENCHGATE TRANSISTOR FOR FLASH; University of Regensburg, Conference: ESSDERC 2000; 93040 Regensburg, Germany; Pages 380-383.
	Hieda, et al.; SUB-HALF-MICROMETER CONCAVE MOSFET WITH DOUBLE LDD STRUCTURE; IEEE Transactions on Election Devices, Vol. 39, No. 3, March, 1992, Pages 671-676.
	Sakao, et al. A STRAIGHT-LINE TRENCH ISOLATION AND TRENCH-GATE TRANSISTOR (SLIT) CELL FOR GIGA-BIT DRAMS; ULSI Device Development Laboratories, NEC Corporation; 1120, Shimokuzawa, Sagamihara, Kanagawa 229, Japan; Pages 19 and 20.

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EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	